Sear	ch N	lotes	

1	Application/Control No.	Applicant(s)/Patent under Reexamination	
1	10/736,087	WALSH ET AL.	
E	Examiner	Art Unit	
1	D. L. Jones	1618	

SEARCHED			
Class	Subclass	Date	Examiner
424	1.11 1.65 1.81 1.85 1.89 9.1	2/24/2006	ΟΊ
544	224 242	2/24/2006	DJ
544	245 253	2/24/2006	DJ
544	254	2/24/2006	DJ
549	200	2/24/2006	DJ
upda	ted	8/10/86	M

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
424	1.11, 1.65 1.81, 1.85	ह्याविवा	
	1.89,9.1		
544	224,242		
	254		
549	200	8/19/01	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventors search STN structure search	2/24/2006	מם	
updated	8/1906	75	
updated interference Search	8/10/00		
Search			
	·		